BUK7212-55B



N-channel TrenchMOS standard level FET Rev. 2 — 23 February 2011

Product data sheet

Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- AEC Q101 compliant
- Low conduction losses due to low on-state resistance
- Suitable for standard level gate drive sources
- Suitable for thermally demanding environments due to 185 °C rating

1.3 Applications

- 12 V and 24 V loads
- Automotive systems

- General purpose power switching
- Motors, lamps and solenoids

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 185 °C		-	-	55	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 3</u> ; see <u>Figure 1</u>	[1]	-	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	167	W
Static chara	acteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{Figure 10}};$ see $\frac{\text{Figure 10}}{\text{Figure 10}}$		-	10.2	12	mΩ



N-channel TrenchMOS standard level FET

Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$I_D = 75 \text{ A}; V_{sup} \le 55 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 ^{\circ}C; \text{ unclamped}$	-	-	173	mJ
Dynamic ch	naracteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V; } I_D = 25 \text{ A;}$ $V_{DS} = 44 \text{ V; } T_j = 25 \text{ °C;}$ see Figure 11	-	12	-	nC

^[1] Continuous current is limited by package.

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain ^[1]	mb	D
3	S	source		
mb	D	mounting base; connected to drain	1 3	mbb076 S
			SOT428 (DPAK)	

^[1] It is not possible to make connection to pin 2.

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7212-55B	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	ı	Min I	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 185 °C	-		55	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-		55	V
V_{GS}	gate-source voltage		-	20 2	20	V
I _D	drain current	$T_{mb} = 25 ^{\circ}\text{C}$; $V_{GS} = 10 \text{V}$; see Figure 1; see Figure 3	<u>[1]</u> _	. {	33	Α
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u> _		59	Α
		T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 3</u> ; see <u>Figure 1</u>	[2] -	. 7	75	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-		335	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-		167	W
T _{stg}	storage temperature		-	55 ′	185	°C
Tj	junction temperature		-	55 ′	185	°C
Source-drain	n diode					
Is	source current	T _{mb} = 25 °C	[2]		75	Α
			<u>[1]</u> _	. {	33	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	. 3	335	Α
Avalanche re	uggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 75 A; $V_{sup} \le$ 55 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-		173	mJ

^[1] Current is limited by power dissipation chip rating.

^[2] Continuous current is limited by package.

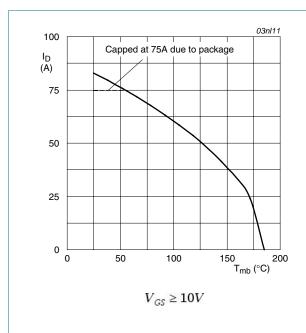


Fig 1. Normalized continuous drain current as a function of mounting base temperature

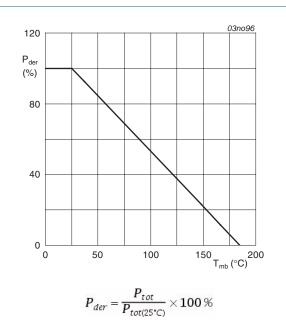
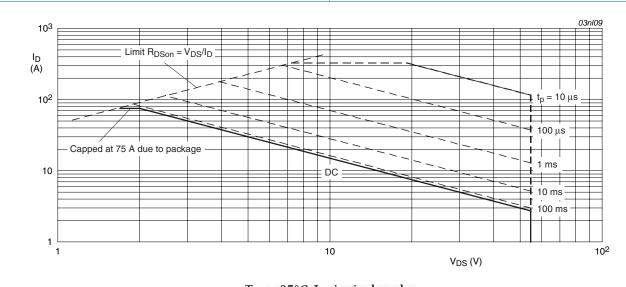


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.95	K/W
R _{th(j-a)}	thermal resistance from junction to ambient		-	71.4	-	K/W

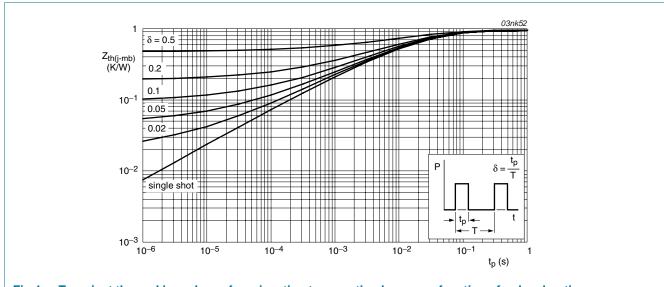


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	55	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	50	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see <u>Figure 8</u>	2	3	4	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 185 °C; see <u>Figure 8</u>	0.9	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 8	-	-	4.4	V
I _{DSS}	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μΑ
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 185 \text{ °C}$	-	-	500	μΑ
lgss	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 185 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	-	25	mΩ
	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9; see Figure 10		-	10.2	12	mΩ
Dynamic c	haracteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$	-	35	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	9	-	nC
Q _{GD}	gate-drain charge		-	12	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	1840	2453	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	379	455	pF
C _{rss}	reverse transfer capacitance		-	165	226	pF
d(on)	turn-on delay time	$V_{DS} = 25 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	18	-	ns
r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	91	-	ns
d(off)	turn-off delay time		-	48	-	ns
t _f	fall time		-	45	-	ns
L _D	internal drain inductance	measured from drain to center of die; $T_j = 25 ^{\circ}\text{C}$	-	2.5	-	nΗ
-s	internal source inductance	measured from source lead to source bond pad; $T_j = 25$ °C	-	75	-	nΗ
Source-dra	ain diode					
V_{SD}	source-drain voltage	I_S = 18 A; V_{GS} = 0 V; T_j = 25 °C; see <u>Figure 13</u>	-	0.85	1.2	V
rr	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	67	-	ns
Q _r	recovered charge	ecovered charge $V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	_	65	-	nC

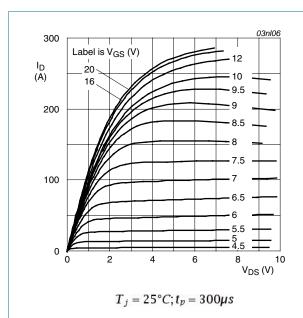


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

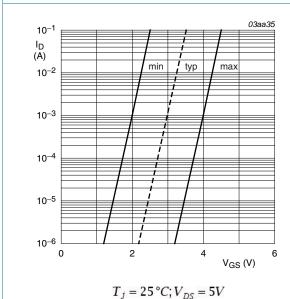
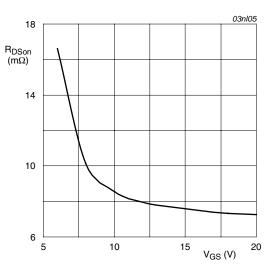
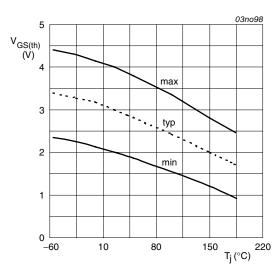


Fig 7. Sub-threshold drain current as a function of gate-source voltage



 $T_j=25^{\circ}C; V_{DS}=25V$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $I_D = 1mA; V_{DS} = V_{GS}$

Fig 8. Gate-source threshold voltage as a function of junction temperature

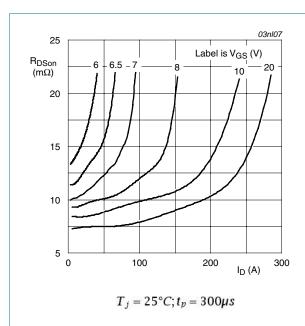


Fig 9. Drain-source on-state resistance as a function of drain current; typical values

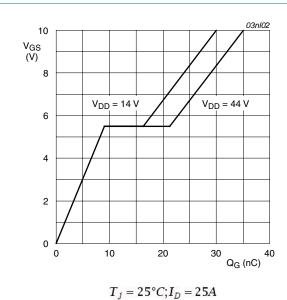


Fig 11. Gate-source voltage as a function of gate charge; typical values

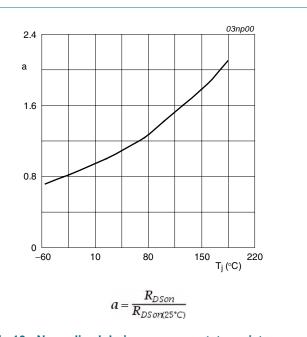
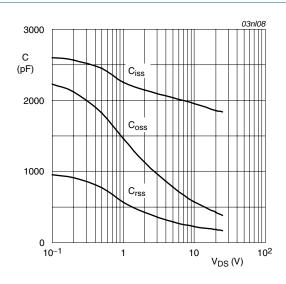


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature



 $V_{GS} = 0V; f = 1MHz$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

N-channel TrenchMOS standard level FET

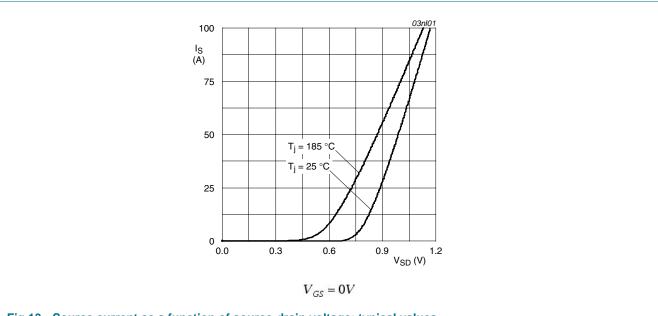


Fig 13. Source current as a function of source-drain voltage; typical values

7. Package outline

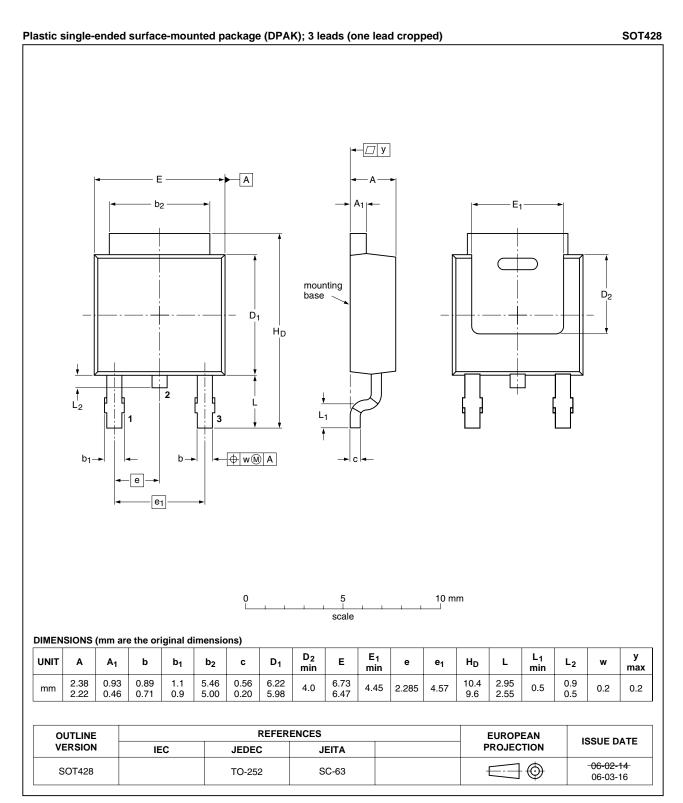


Fig 14. Package outline SOT428 (DPAK)

N-channel TrenchMOS standard level FET

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
BUK7212-55B v.2	20110223	Product data sheet	-	BUK7212_55B-01		
Modifications:	 The format of of NXP Semic 		data sheet has been redesigned to comply with the new identity guideline uctors.			
	 Legal texts ha 	ve been adapted to the new	company name where	appropriate.		
BUK7212_55B-01 (9397 750 12229)	20040123	Product data	-	-		

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BUK7212-55B

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N-channel TrenchMOS standard level FET

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BUK7212-55B

N-channel TrenchMOS standard level FET

11. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	2
3	Ordering information	2
4	Limiting values	3
5	Thermal characteristics	5
6	Characteristics	6
7	Package outline	
8	Revision history	
9	Legal information	
9.1	Data sheet status	
9.2	Definitions	
9.3	Disclaimers	
9.4	Trademarks	
10	Contact information	12

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